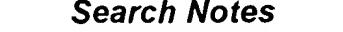


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/762,127	NAGAISHI ET AL.
	Examiner Chongshan Chen	Art Unit 2162

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner